

SUPPORTING INFORMATION

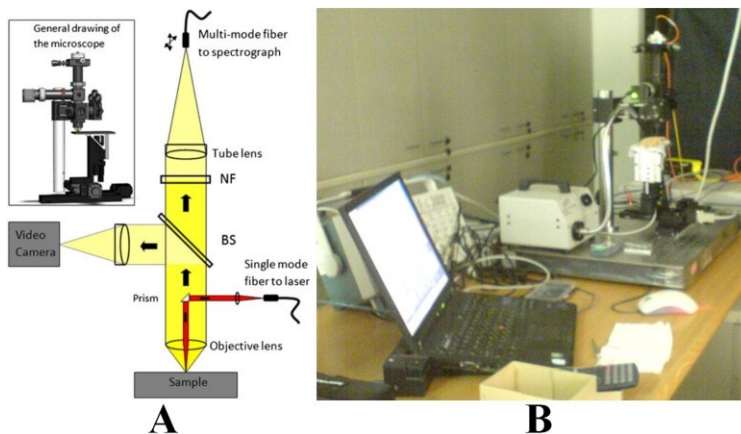


Figure S1. The Confocal Raman Microscope: (A) A sketch of the device, comprised of a 671 nm laser, lens system, beamsplitter (BS), Raman notch filter (NF), a spectrograph, an auto-focus mechanism based on a digital camera, and a 3-D scanning table; (B) A photograph of the laboratory setup.

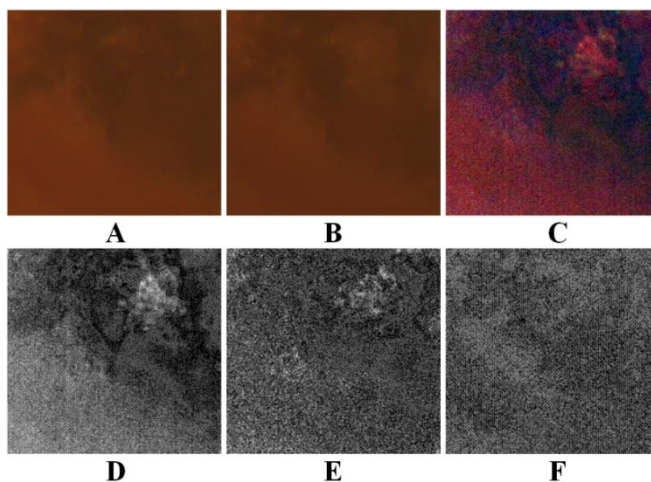


Figure S2. An example of damage induced by the laser, experiment A/4 (EIF = 56.8): (A) prior to the experiment; (B) following the experiment; (C) difference RGB image; (D) R band difference image; (E) G band difference image; (F) B band difference image.

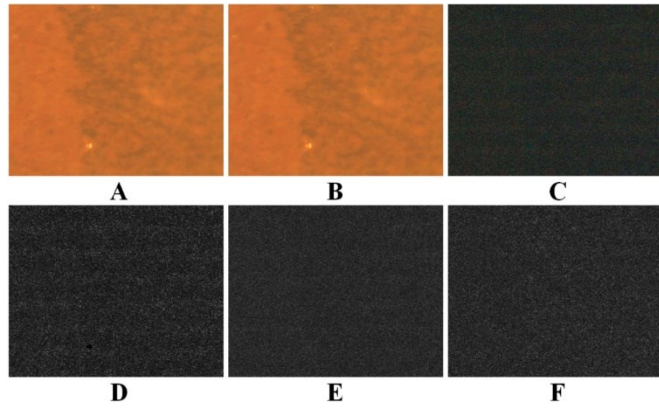


Figure S3. An example of lack of damage induced by the laser, experiment B/3 (EIF = 3.8): (A) prior to the experiment; (B) following the experiment; (C) difference RGB image; (D) R band difference image; (E) G band difference image; (F) B band difference image.

Table S1. Damage experiments details, detailing the EIF (Energy Increase Factors) with respect to the final setting.

Set / Number	Settings							Results
	Laser wave-length	Laser beam diameter	Effective power	Sampled area	Step size	Duration at each pixel	EIF	
A / 1	532 nm	0.5 μm	5 mW	20 μm strip	0.25 μm (overlap)	60 sec.	54487	damage
A / 2	532 nm	0.5 μm	1.25 mW	20 μm strip	0.25 μm (overlap)	60 sec.	13622	damage
A / 3	532 nm	0.5 μm	1.25 mW	20 μm strip	0.25 μm (overlap)	0.5 sec.	113.5	damage
A / 4	532 nm	0.5 μm	1.25 mW	20x20 μm^2 square grid	0.5 μm	0.5 sec.	56.8	damage
B / 1	532 nm	30 μm	5 mW	Single pixel	-	100 sec.	12.6	no damage
B / 2	532 nm	30 μm	5 mW	1000 μm strip	10 μm (overlap)	1 sec.	0.38	no damage
B / 3	532 nm	30 μm	5 mW	500 μm strip	10 μm (overlap)	10 sec.	3.8	no damage
Final device	671 nm	30 μm	5 mW	varies	30 μm	1 sec. $\times$ 10 samples	1	no visible damage